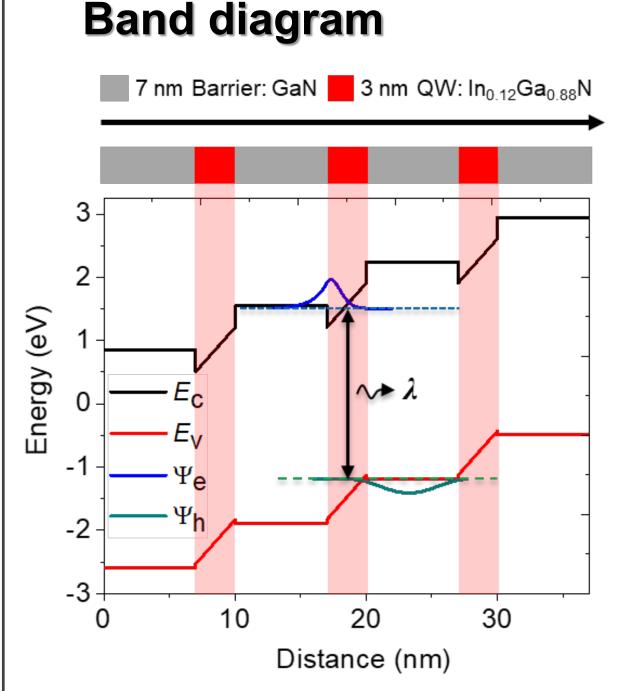
MBE-Grown III-Nitride Based Blue Laser Diodes on c-plane GaN Substrates

MOTIVATION

Automotive lighting **Visibility Range** LED high beam completed by the laser-light booster LED high bean Low beam Blue lasers

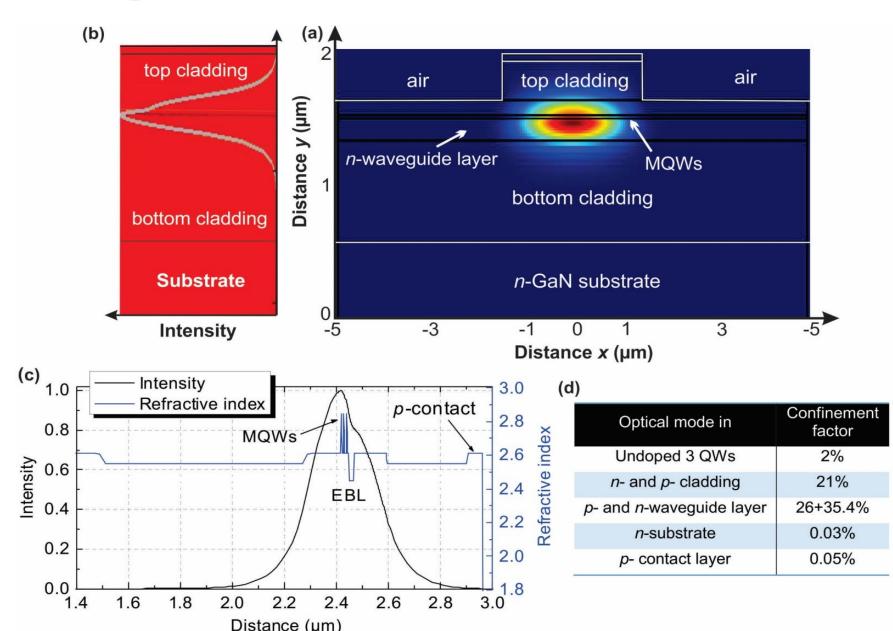
Improved visibility, resulting in increased road traffic safety. Laser-based headlights will have the longest range provided by any current headlight technology

DEVICE DESIGN



Waveguide simulation

- Simulated equilibrium energy band diagram of the active region
- 3 compressively strained 3-nm-thick InGaN quantum wells
- Symmetric Fabry-Pérot structure

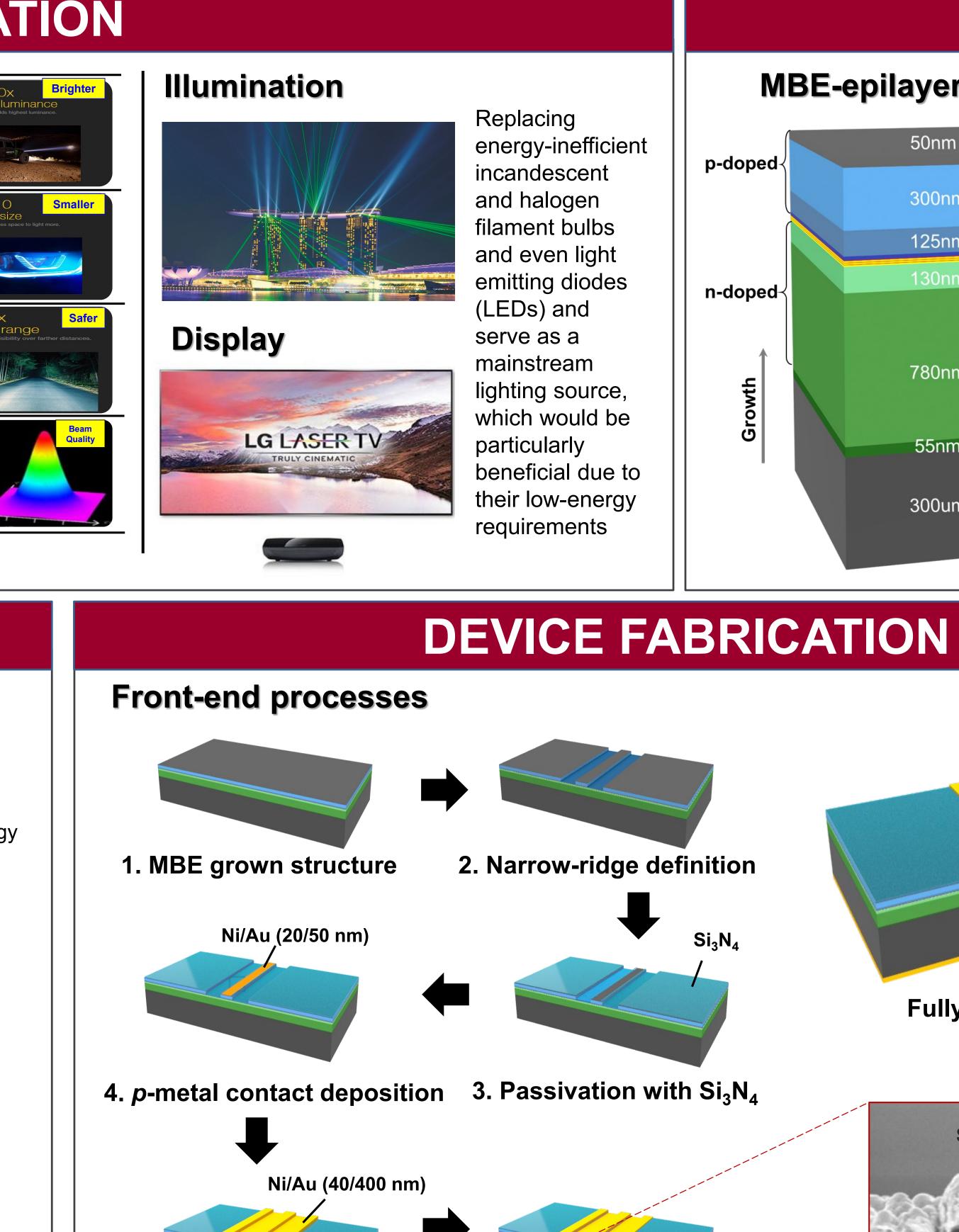


(a) Cross section of a laser structure along with a 2D surface plot of the light intensity of the fundamental transverse mode, (b) 1D intensity distribution of the fundamental TE-mode in the waveguide, (c) refractive index profile and mode intensity distribution, and (d) confinement factors in several sections of the laser structure.



THE OHIO STATE UNIVERSITY

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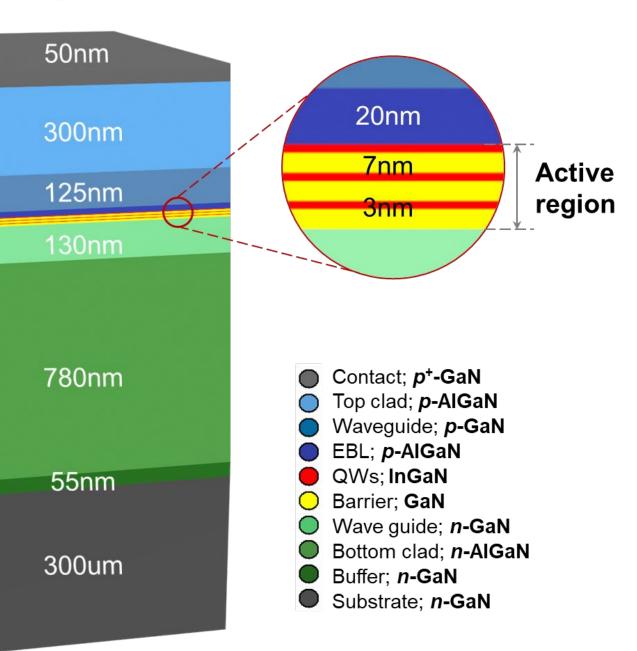
Ni/Au (20/100 nm) 5. *p*-metal pad deposition 6. *n*-metal contact deposition Back-end processes and stand of the

Scribing and breaking

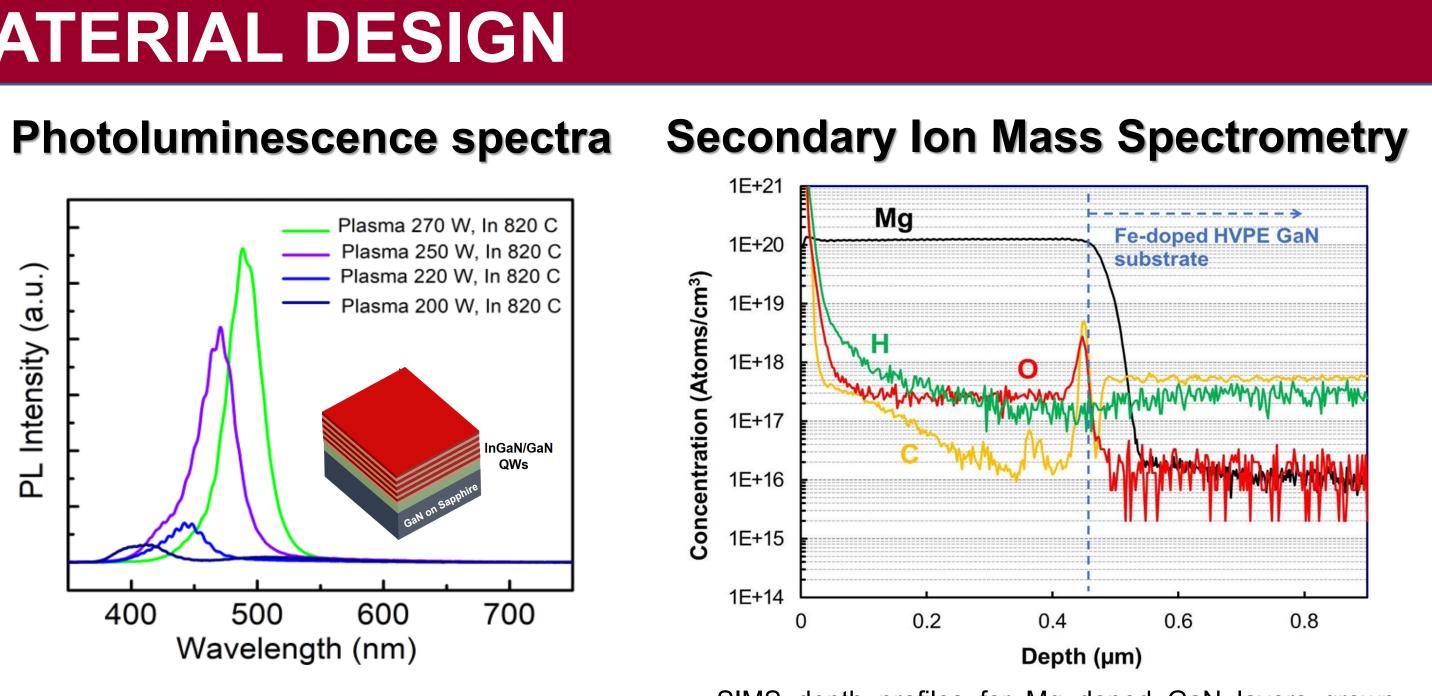
Mounting

2019 OSU Materials Week

MBE-epilayers of blue laser

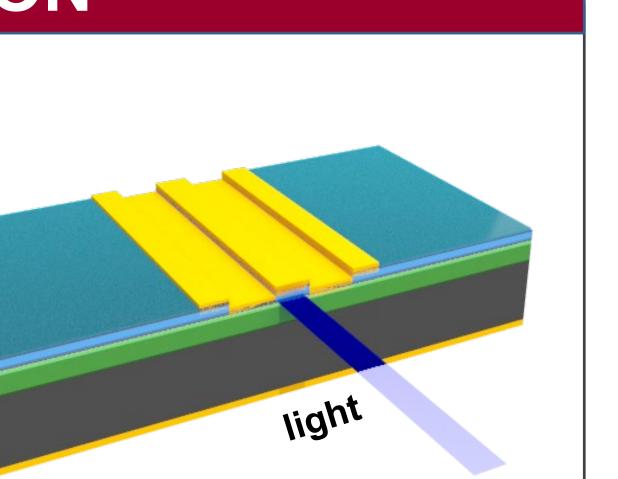


MATERIAL DESIGN

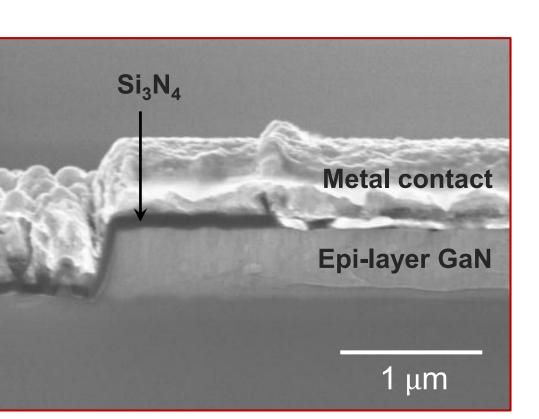


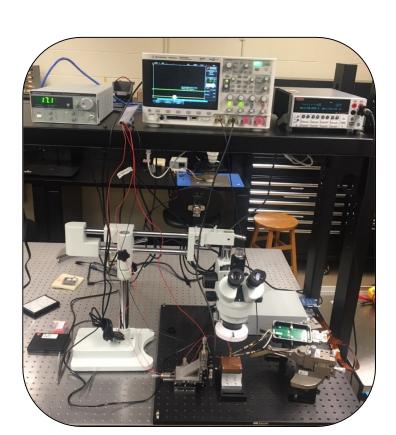
PL spectra for planar InGaN/GaN quantum wells grown with same indium flux and varied plasma power. Schematic illustration of the PL structure grown on GaN-on-Sapphire substrate is shown as an inset



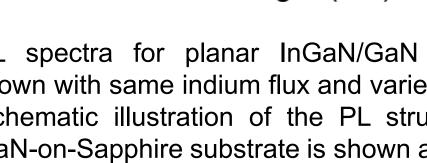


Fully-processed blue laser

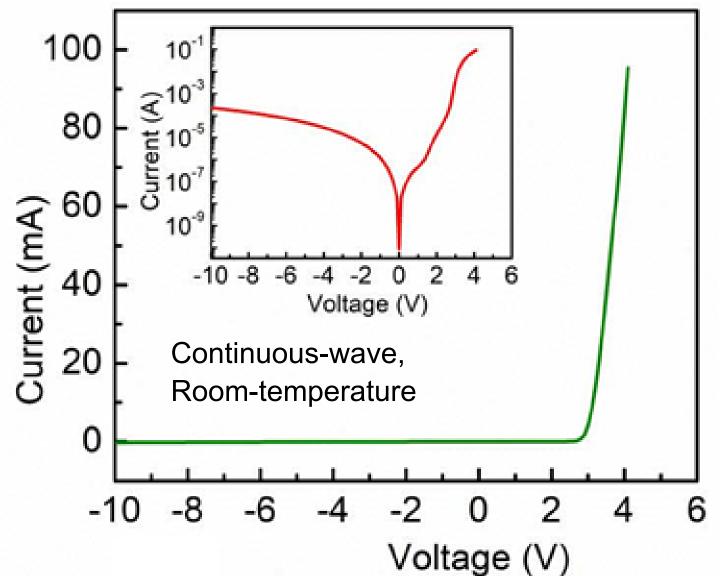




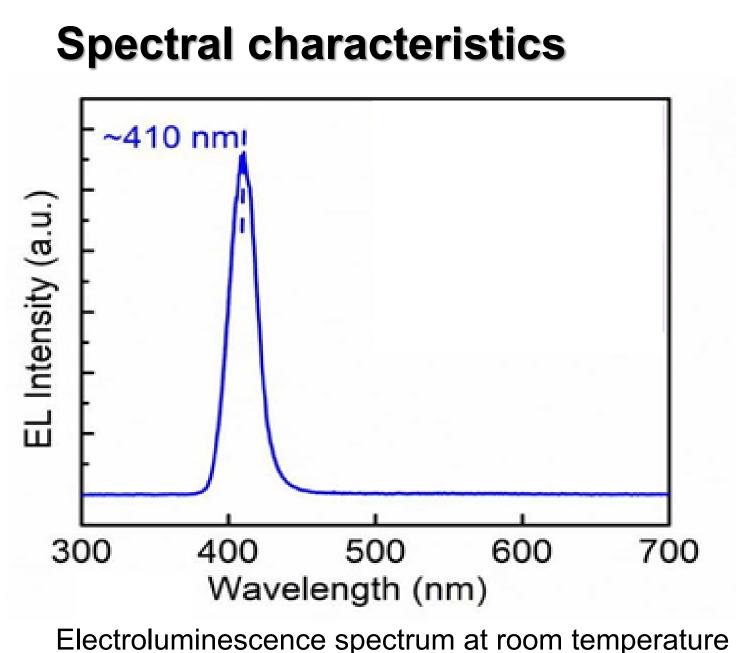
Probing



I-V characteristics



I-V characteristics of a ridge laser with 20 µm × mm in linear scale. Device exhibits good turn-on and low dark current. Semi-logarithmic plot shown as inset.







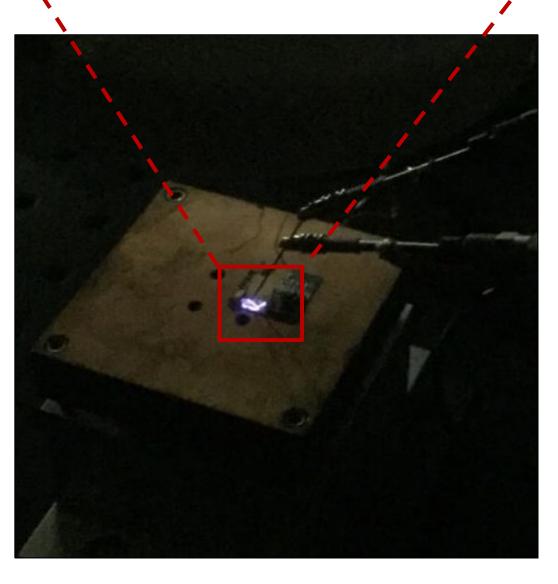
*arafin.1@osu.edu

SIMS depth profiles for Mg doped GaN layers grown under nitrogen rich condition (III/V = 0.8 : 1) but with Ga flux interruption. The growth temperature was 580°C, and Mg beam equivalent pressure at 4x10⁻¹⁰ Torr.

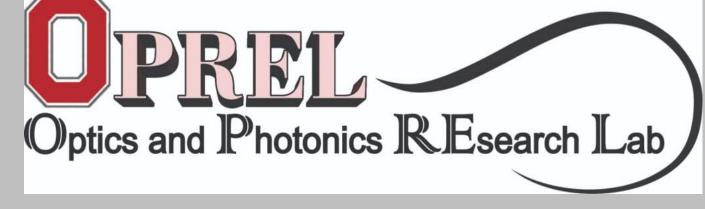
DEVICE RESULTS

Device under test





Devices exhibit strong electroluminescence at room temperature even at a current density of 20 kA/cm². No lasing is yet observed. The reason of this non-lasing behavior could be due to unoptimized active region that will be investigated.



https://oprel.engineering.osu.edu/